


<b>Search Notes</b>  	<b>Application/Control No.</b>  10599107	<b>Applicant(s)/Patent Under Reexamination</b>  TAGAWA ET AL.
	<b>Examiner</b>  Son T Nguyen	<b>Art Unit</b>  3643

SEARCHED			
Class	Subclass	Date	Examiner
47	1.01P,1.01R,1.7	4/8/10	stn
111	114,104,105	4/8/10	stn
414	416.09,416.11	4/8/10	stn
198	468.6	4/8/10	stn

SEARCH NOTES		
Search Notes	Date	Examiner
Foreign IPC search, see printouts	4/8/10	stn
Consulted with primaries J.Keenan (class 414) and J.Bidwell (class 198)	4/8/10	stn

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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